

3rd IEEE Design for Reliability and Variability Workshop (DRVW) 2011

Advance Program

May 4 (Wednesday)

4:00 pm -- 4:15 pm	Opening Remarks Michael Nicolaidis, General Co-Chair Yervant Zorian, General Co-Chair Virendra Singh, Program Co-Chair
4:15 pm -- 5:00 pm	Keynote 1 Speaker: Melvin Breuer (Univ. of Southern California) Topic: The Three R's: Reliability, Redundancy, and Reconfigurability
5:00 pm -- 5:30 pm	Invited Talk 1 Speaker: Tim Cheng (Univ. Of California, Santa Barbara) Topic: DfX in the Late-Silicon Era
5:30 pm – 6:00 pm	BREAK
6:00 pm – 6:30 pm	Invited Talk 2 Speaker: Abhijit Chattrejee (Georgia Tech) Topic: Variability and Mixed Signal Design
19:00:00	Social Event

May 5 (Friday)

8:00 am – 8:30 am	Keynote 2 Masahiro Fujita (Tokyo University) Topic: Patchable Hardware Design
8:45 am – 9:30 am	Keynote 3 Diana Marculescu (Carnegie Mellon University) Topic: Symbolic Reliability Modeling, Analysis, and Optimization
9:30 am – 10:30 am	Session 1 1.1 Criticality of Configuration Bits in SRAM-based FPGAs: Predictive Analysis and Experimental Results Lorena Anghel, Jean-Baptiste Ferron, and Regis Leveugle (TIMA, France) 1.2 Variability-aware Task mapping strategies for Many-cores processor chips Fabien Chaix, Gilles Bizot, Michael Nicolaidis, and Nacer-Eddine Zergainoh (TIMA, France)
10:30 am – 11:00 am	BREAK

11:00 am – 12:00 am	<p style="text-align: center;">Session 2 (Invited talks)</p> <p>2.1 Speaker: Kanak Agrawal (IBM) Topic: Addressing Process Variability Challenges through better Coupling between Design and Technology</p> <p>2.2 Speaker: Adit Singh (Auburn University) Topic: Detecting Reliability Defects within Random Parameter Variation</p>
12:00 noon – 1:45pm	LUNCH
1:45 pm – 2:45 pm	<p style="text-align: center;">Session 3 (Invited talks)</p> <p>3.1 Speaker: Cecilia Metra (Univ. Of Bologna) Topic: Processor Parameter & Clock Variation: How We Can Deal with Them in High Performance Microprocessors</p> <p>3.2 Speaker: Speaker: Abhilash Goyal, Topic: Self-Calibrating Architectures for Low-Cost and High-Yield Systems</p>
2:45 pm – 4:15 pm	<p style="text-align: center;">Panel Discussion</p> <p>Topic: Variability and Reliability: Will they Get Better or Worse in Future CMOS Technologies ?</p> <p>Moderator: Subhasis Mitra (Stanford University)</p> <p>Panelists:</p> <p>Peter Koeppen, TI</p> <p>Puneet Gupta, UCLA</p> <p>TBD</p> <p>TBD</p> <p>TBD</p>
4:15 pm	Wrap-up